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| Notice of References Cited | Application/Control No. 10/674,020 | Applicant(s)/Patent Under Reexamination TAJIMA ET AL. | |
| | Examiner Eduardo Colon-Santana | Art Unit 2837 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------|----------------|
| | A | US-5,585,709 | 12-1996 | Jansen et al. | 318/807 |
| | B | US-5,969,500 | 10-1999 | Ishikawa et al. | 318/807 |
| | C | US-6,184,647 | 02-2001 | Oguro et al. | 318/727 |
| | D | US-6,198,256 | 03-2001 | Miyazaki et al. | 318/140 |
| | E | US-2002/0113569 A1 | 08-2002 | Iijima et al. | 318/727 |
| | F | US-6,456,030 | 09-2002 | Masaki et al. | 318/700 |
| | G | US-6,677,724 | 01-2004 | Kim et al. | 318/700 |
| | H | US-6,700,400 | 03-2004 | Atarashi, Hirofumi | 318/254 |
| | I | US-6,707,265 | 03-2004 | Imai et al. | 318/254 |
| | J | US-2005/0007044 A1 | 01-2005 | Qiu et al. | 318/254 |
| | K | US-2005/0029972 A1 | 02-2005 | Imai et al. | 318/254 |
| | L | US-2005/0057208 A1 | 03-2005 | Seibel et al. | 318/432 |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
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| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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